

Search Notes**Application/Control No.**

10/805,023

Examiner

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Applicant(s)/Patent under Reexamination

IKEDA ET AL.

Art Unit

3629

SEARCHED

Class	Subclass	Date	Examiner
705	1	10/05	DN
	6		1
	7		
	8		
	9		
	10		
707	5		
713	200		
395	600		
	650		
	700	↓	↓

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
I USP 1) PGPub 2) Patent	10/05	DN
II FOREIGN		
1. EPO		
2. JPO		
3. Derwent		
4. IBM TDB	↓	↓

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner